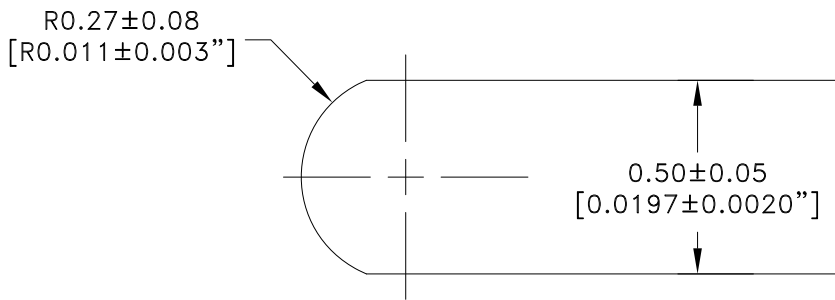
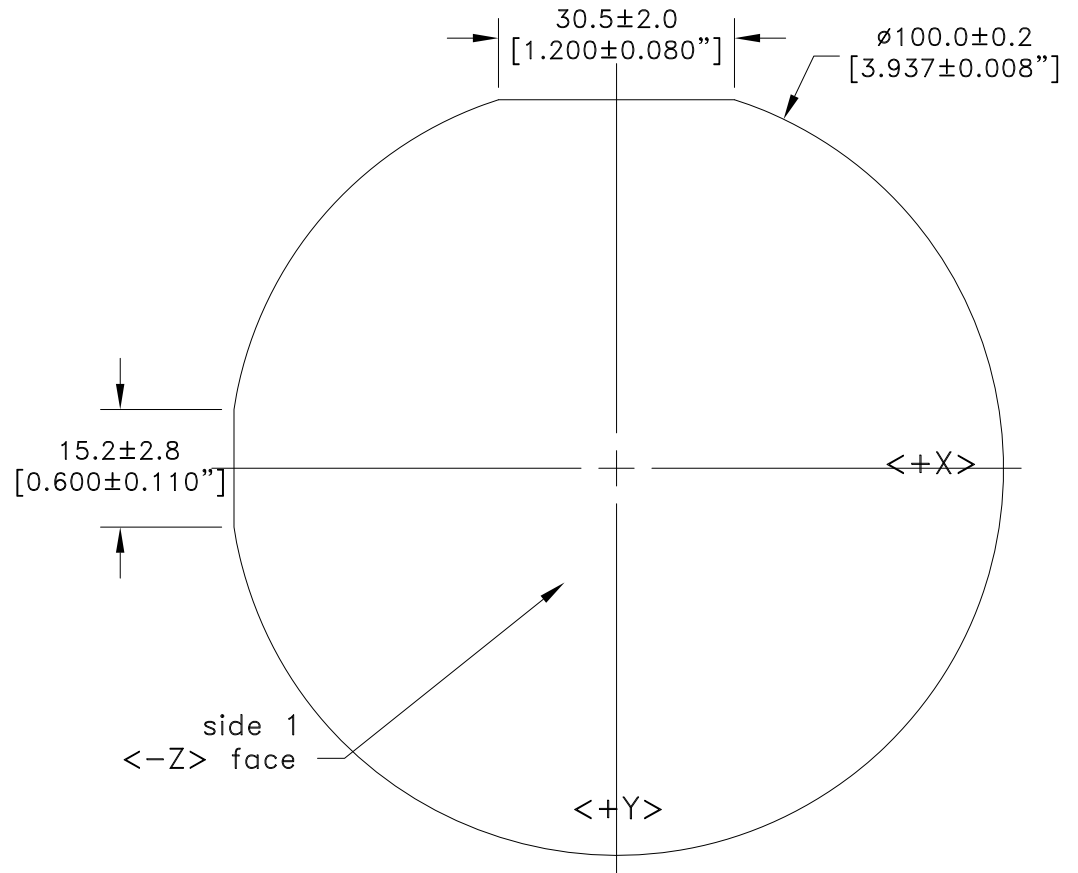


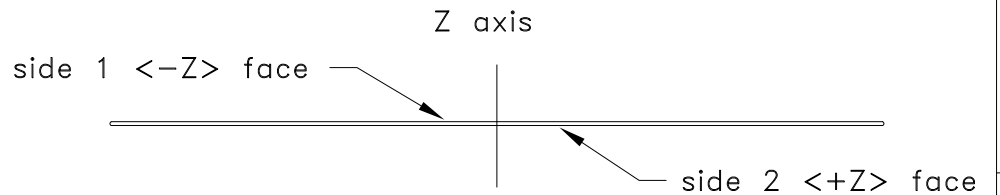
Notes:

- 1.0 Material
 - 1.1 Lithium Niobate optical grade
- 2.0 Orientations
 - 2.1 Wafer surface is normal to $\langle Z \rangle \pm 0.2^\circ$
 - 2.2 Flats
 - 2.2.1 Primary flat is normal to $\langle -Y \rangle \pm 0.2^\circ$.
 - 2.2.2 Secondary flat is $90^\circ \pm 1^\circ$ counter clockwise from primary flat when viewing the $-Z$ face.
- 3.0 Edge
 - 3.1 All edges rounded with $R0.27 \pm 0.08\text{mm}$.
 - 3.2 No more than 2 edge chips greater than 0.25mm in penetration and 0.5mm in length.
- 4.0 Surfaces
 - 4.1 Side 1 $\langle -Z \rangle$ face
 - Polished 10-5 scratch-dig with 1mm edge exclusion.
 - No pits or scratches visible with reflected light and unaided eye.
 - 4.2 Side 2 $\langle +Z \rangle$ face
 - Polished 20-10 scratch-dig with 1mm edge exclusion.
 - Light pits and scratches visible with reflected light and unaided eye allowed.
- 5.0 Flatness
 - 5.1 warp $< 20\mu\text{m}$
 - 5.2 TTV $< 10\mu\text{m}$
- 6.0 Measurements, Documentation, and Shipping
 - Supply certificate of compliance 97-01517-13-100.

Document
01/31/14
Control



Wafer Edge Detail, 50X



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Material: Lithium Niobate	DR. Scholz	03/25/03	
Unless otherwise specified, dimensions in mm	CHK.		
Tolerances			Title: LNIO 100 ϕ x 0.5mm, $-Z$ Po/Po $-Y$ FLT, TTV $<10\mu\text{m}$, top
Inches	Millimeters	Wafer Code: LNA--Z:100.050DN	
.X \pm 0.1 .XX \pm 0.01 .XXX \pm 0.005 .XXXX \pm 0.0020	X \pm 0.5 X \pm 0.25 XX \pm 0.1 XXX \pm 0.05	Customer Approval:	Size: A
Angles \pm 0.5°			Dwg. No: 97-01517-13
DO NOT SCALE DRAWING			Rev: A
			Scale: 1:1
			Sheet 1 of 1